


<b>Search Notes</b> 	<b>Application/Control No.</b> 10723664	<b>Applicant(s)/Patent Under Reexamination</b> BURKE ET AL.
	<b>Examiner</b> RICHARD CHAN	<b>Art Unit</b> 2618

SEARCHED			
Class	Subclass	Date	Examiner
455	574, 552.1, 550.1, 572, 343.1	8/1/08	RC

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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